

<b>Notice of References Cited</b>	Application/Control No. 10/618,145	Applicant(s)/Patent Under Reexamination FENG ET AL.	
	Examiner James L Habermehl	Art Unit 2651	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0233568 A1	11-2004	Rao et al.	360/075
	B	US-2002/0097517 A1	07-2002	Bonin et al.	360/75
	C	US-5,901,014 A	05-1999	Hiraoka et al.	360/234.5
	D	US-6,700,724 B2	03-2004	Riddering et al.	360/69
	E	US-6,775,089 B1	08-2004	Bonin et al.	360/75
	F	US-2003/0043497 A1	03-2003	Riddering et al.	360/75
	G	US-6,359,746 B1	03-2002	Kakekado et al.	360/75
	H	US-6,757,120 B2	06-2004	Minoshima et al.	360/75
	I	US-6,577,466 B2	06-2003	Meyer et al.	360/75
	J	US-6,621,661 B1	09-2003	Ichikawa et al.	360/234.5
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.